

Notice of References Cited

Application/Control No.

09/819,250

Applicant(s)/Patent Under

Reexamination

OZAKI ET AL.

Examiner

BRIAN P. YENKE

Art Unit

2614

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-2003/0016304	01-2003	NORSWORTHY et al.	348/565
B	US-2002/0057372	05-2002	Cavallerano et al.	348/565
C	US-6,493,038	12-2002	Singh et al.	348/565
D	US-6,603,517	08-2003	Shen et al.	348/565
E	US-6,459,906	10-2002	Yang, Jae-Duk	455/556.1
F	US-6,621,526	09-2003	Yamagishi, Toru	348/659
G	US-6,532,041	03-2003	Monta et al.	348/468
H	US-5,671,019	09-1997	Issoe et al.	348/565
I	US-5,557,338	09-1996	Maze et al.	725/38
J	US-6,556,252	04-2003	Kim, Dae Joong	348/565
K	US-5,978,046	11-1999	Shintani, Peter	348/589
L	US-5,708,475	01-1998	Hayashi et al.	348/468
M	US-5,602,598	02-1997	Shintani, Peter	348/565

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
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P					
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R					
S					
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NON-PATENT DOCUMENTS

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,308,329	10-2001	Takahashi, Naomasa	725/153
B	US-2002/0181936	12-2002	Yuen et al.	386/83
C	US-5,999,207	12-1999	Rodriguez et al.	348/14.03
D	US-6,061,099	05-2000	Hostetler, David A.	348/584
E	US-6,210,170	04-2001	Sorensen et al.	434/323
F	US-5,946,046	08-1999	You et al.	348/468
G	US-6,141,058	10-2000	Lagoni et al.	348/563
H	US-6,175,387	01-2001	Han, Dongil	348/565
I	US-6,226,047	05-2001	Ryu, Choong-IL	348/569
J	US-6,268,887	07-2001	Watanabe et al.	348/554
K	US-6,384,868	05-2002	Oguma, Tadashi	348/564
L	US-6,421,094	07-2002	Han, Dongil	348/569
M	US-6,510,553	01-2003	Hazra, Rajeeb	725/87

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-2002/0033899	03-2002	OGUMA, TADASHI	348/565
B	US-2002/0104081	08-2002	Candelore et al.	725/9
C	US-2003/0020832	01-2003	Carlsgaard et al.	348/565
D	US-5,422,677	06-1995	Do, Young S.	348/568
E	US-5,565,929	10-1996	Tanaka, Shigeo	348/565
F	US-5,675,389	10-1997	Oda, Osamu	348/468
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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